METHOD AND APPARATUS FOR WAVEFORM QUALITY MEASUREMENT

Publication number: EP1342335
Publication date: 2003-09-10
Inventor: MONTOJO JUAN (US); SINDHUSHAYANA NAGABHUSHANA (US); BLACK PETER (US)
Applicant: QUALCOMM INC (US)
Classification:
- international: ***H04B1/707; H04B1/00; H04B17/00;*** **H04B1/707; H04B1/00; H04B17/00;** (IPC1-7): H04L1/24
- European: H04B17/00B1
Application number: EP20010990097 20011213
Priority number(s): WO2001US47758 20011213; US20000738586 20001214

Also published as:
WO0249221 (A3)
WO0249221 (A2)
US6693920 (B2)
US2004114505 (A1)
US2002114353 (A1)

more >>

Report a data error here

Abstract not available for EP1342335
Abstract of corresponding document: **WO0249221**

A method and an apparatus for waveform quality measurement are disclosed. An actual signal, representing a waveform channelized both in time and in code is generated by, e.g., an exemplary HDR communication system. Test equipment generates an ideal waveform corresponding to the actual waveform. The test equipment then generates an estimate of offsets between parameters of the actual waveform and the ideal waveform, and the offsets are used to compensate the actual waveform. The test equipment then evaluates various waveform quality measurements utilizing the compensated actual waveform quality measurements as well as conceptual and practical examples of processing of the actual waveform and the corresponding ideal waveform by the test equipment are disclosed. The disclosed method and apparatus may be extended to any waveform channelized both in time and in code regardless of the equipment that generated the waveform.